TC-1 • Terminal Rhanactoristics 0G Actino Denices : ••• ; ; ••• NPN BJT .,, Ic VCE ••• VCE ••• ス ••• IB IB3 IRZ IBI t IBS - - -. . . Τc I BY ••• ~ . . I B3 . . . : IB1 11 ••• VCE • • • Characteristic . . . Output . . . :...

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76-5 N Channel Enhancement Mode MOSFET MO FET ----D ••• ĮΙD B O ••• G 0 • • • O estput Caracteristic ... S VGS , ID Vps С Vps VGS VG3 . . . ID ... VGZ VGS1 VOS · · · · · , **,** ,

ID . . . VGSID2 ID, • • • . . . Vos Vz \vee_{ι} $\frac{D ID}{D V_{DS}}$ ID2 - IDI VD2 - VDI the channel length modulation bactor 11 \sum (7.50) \mathbf{b} ID VDS • • • . . . IDI + IDZ ID . . .)) 2 VZ V_{l} + $\bigvee DS$ 2

TC-6

TC-1 Nin the SPICE parameter LAMBDA $I_{D} = H \left[V_{GS} - V_{TO} \right]^{2}$ $\sqrt{I_{D}} = \sqrt{H} \left[V_{GS} - V_{TO} \right] (7.5)$ strought line with slope VFT y intercept - JFT VTO Find VTO & K $T_0 = \frac{T}{1 + \lambda V_{DS}}$, K = 2 h. (7.52)H' is the SPICE paramete ΗP El Vio is the SPICE parameter $\vee \tau o$ and the second second



Drain Current in mA



m := slope(vx, vy) b := intercept(vx, vy) K := m² $V_{TO} := \frac{-b}{m}$ K = 1.993 × 10⁻⁴

$$V_{TO} = 1.494$$



Note that slope and intercept are built in MathCad functions.

If a CSV file of data from the curve tracer is desired do the following:

- Get the desired display on the screen of the curve tracer either manually or with the LabVIEW program.
- Press Local on the physical Tektronix 370B Curve Tracer. This returns control of the instrument to the knobs and buttons.
- Insert a formatted high quality double density floppy disk into the floppy disk drive on the curve tracer.
- Simultaneously press the buttons: SHIFT, ADDR, & BMP FILE. The display should indicate that a CSV file is being printed to the floppy disk.
- When the LED on the drive goes out remove the floppy disk.
- Press the RUN button on the LabVIEW program to return control of the instrument to the pc.



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Georgia Institute of Technology

School of Electrical and Computer Engineering

ECE 3042	Microelectronic Circuits Laboratory	Verification Sheet
NAME:	SECTION	N:
GT NUMBER:	GTID:	

Experiment 7: Terminal Characteristics of Active Devices

Procedure	Time Completed	Date Completed	Verification (Must demonstrate circuit)	Points Possible	Points Received
1. NPN BJT Output				14	
2. NPN BJT Transfer				14	
3. PNP BJT Output				14	
4. PNP BJT Transfer				14	
5. N MOSFET Output				14	
6. P MOSFET Output				14	
7. JFET Output				16	

To be permitted to complete the experiment during the open lab hours, you must complete at least **four** procedures during your scheduled lab period or spend your entire scheduled lab session attempting to do so. A signature below by your lab instructor, Dr. Brewer, or Dr. Robinson permits you to attend the open lab hours to complete the experiment and receive full credit on the report. Without this signature, you may use the open lab to perform the experiment at a 50% penalty.

ECE 3042 Check-off Requirements for Experiment 7

Make sure you have made all required measurements before requesting a check-off. For all check-offs, you must demonstrate the circuit or measurement to a lab instructor.

- A labview program is used to control the curve tracer.
- For each transfer characteristic, use a cursor to obtain one (Ic, Vbe) point on the curve.
- For each output characteristic, use cursors to find five (I, V) points on five separate curves for a constant Vce or Vds. For a constant Vce or Vds, the cursors should be on the same vertical line. Also, determine the slope of one of the upper characteristic curves.

For the report, determine the dominant SPICE parameters for the devices from the measured curves and simulate the characteristic curves. Compare the simulated curves to the measured curves by creating a table that displays the points measured in lab on the curve tracer to the corresponding points on the simulated curves. Use the same x axis voltage as was used in lab and measure the simulated current. In the report, group together the measured curve, calculations of the device parameters, the table comparing the measured and modeled values, and the simulated curve for each device.